Term project (Ver 1.1)

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Revision history

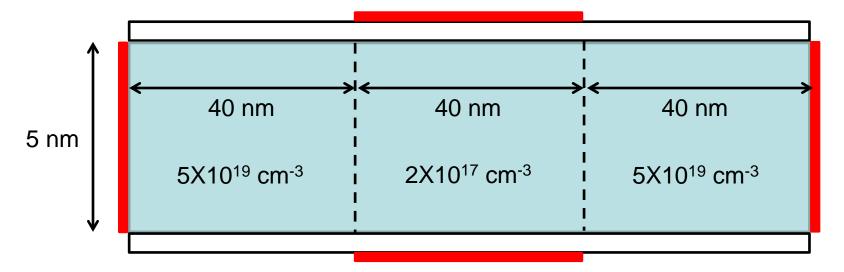
- Nov 25: Ver 1.0
 - Initial version
- Nov 26: Ver 1.1
 - Modify the Boltzmann equation part. Elastic scattering.

Term project (1)

- Due: AM08:00, <u>December 17</u> (No delayed submission)
- Your code and report should be submitted.
- There are many steps in the term project.
 - Nonlinear Poisson
 - Drift-diffusion
 - Schrödinger
 - Boltzmann

Term project (2)

- Double-gate
 - 5-nm-thick silicon & 0.5-nm-thick oxide at both sides
 - 40-nm-long gate (Workfunction: 4.3 eV)



Term project (3)

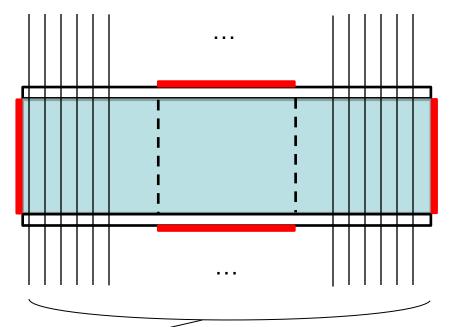
- Solve the nonlinear Poisson equation for the double-gate structure.
- $V_S = V_D = 0$ and V_G varies from 0 V to 1 V. (0.1 V step)
- Draw ϕ and n. (3D plot)

Term project (4)

- Solve the drift-diffusion equation for the double-gate structure.
- Self-consistent simulation is mandatory.
- $-V_{S}=0$
- V_G varies from 0 V to 1 V. (0.1 V step)
- V_D varies from 0 V to 1 V. (0.1 V step)
- For each V_G , draw the drain current (I_D) as a function of V_D .
- The electron mobility is assumed to be 1430 cm²/V sec.

Term project (5)

- Solve the Schrödinger equation.
- Use ϕ obtained in Step2.
- (Non-self-consistent simulation)
- $-V_{S}=0$
- Consider V_G of 0.1 V and 0.5 V.
- Consider V_D of 0.1 V and 0.5 V.
- Consider three different valleys.
- Calculate the lowest subband for each slab.



Term project (6)

- Solve the Boltzmann equation. (Only an elastic scattering with $\tau = 0.1$ psec is considered.)
- For each valley, only the lowest subband is considered.
- Use ϕ obtained in Step2. (Non-self-consistent simulation)
- $-V_{S}=0$
- Consider V_G of 0.1 V and 0.5 V.
- Consider V_D of 0.1 V and 0.5 V.
- Calculate the drain current (I_D) for the four cases.
- For each case, draw f_0 of each valley. (3D plot)